Form 1449 (Modified)	Atty Docket No.	Application No.:		
	01-471/1D / LSI1P172D1	Filed Herewith		
Information Disclosure	Applicant:	10/772 133		
Statement By Applicant	CATABAY et al.	7		
	Filing Date $2/3/04$	Group		
(Use Several Sheets if Necessary)	Herewith	Unassigned		

U.S. Patent Documents

Examiner						Sub-	Filing
Initial %	No.	Patent No.	Date	Patentee .	Class	class	Date
77/	Α	5,925,415	07/20/99	Fry et al.	427	304	03/09/98
/	В	6,010,962	01/04/00	Liu et al.	438	687	02/12/99
	С	6,015,749	01/18/00	Liu et al.	438	628	05/04/98
	D	6,022,808	02/08/00	Nogami et al.	438	694	03/16/98
	E	6,037,258	03/14/00	Liu et al.	438	687	05/07/99
	F	6,042,889	03/28/00	Ballard et al.	427	305	02/28/94
	G	6,066,892	05/23/00	Ding et al.	257	751	05/14/98
	Н	6,162,727	12/19/00	Schonauer et al.	438	687	11/25/98
V	I	6,235,406	05/22/01	Uzoh	428	620	07/13/00

Foreign Patent or Published Foreign Patent Application

Examiner		Document	Publication	Country or		Sub-	Trans	slation
Initial	No.	No.	Date	Patent Office	Class	class	Yes	No
	J			/				
H.	K			7				
	L			/				
	M							
	N		/					

Other Documents

		Other Documents
Examiner		
Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
71	0	Wolfe, et al., Silicon Processing for the VLSI Era, Vol. 1 – Process Technology, 2 nd Ed., Lattice Press: Sunset Beach, CA, 2000, pp. 791-795.
TN	P	U.S. Patent Application No. 10/035,705, "Electroless Deposition of Copper to Form Copper Interconnect Structures", filed 10/18/01.
	Q	
Examiner		T. Nhunten Date Considered 4/6/06

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

CATABAY et al. Filing Date Light Class Group Unassigned Catabay Cataba	Form 1449 (Modified) Information Disclosure				Atty Docket No. 01-471/1D / LSI1P1' Applicant:	72D1	Application No.: Filed Herewith			
Class Sub- Class Date Date Patente Class Class Date				- 1		10 772 133				
U.S. Patent Documents Examiner No. Patent No. Date Patentee Class Class Date Patentee Class Class Date Patentee Class Class Date Patentee Class Patentee Class Date Patentee Class Patentee Patentee Class Patentee Patentee Class Patentee Patentee Patentee Class Patentee Patentee Patentee Patentee Patentee Patentee Pa	Si	atemer	it by Applicar				C			
Second Content Conte	(Llas S	'arrama1	Chasta (CNIssa)		- // 5/0	4	-			
Examiner	(Use s	everar	Sheets II Nece	ssary)	rierewith	•				
Initial				U.S. Paten	t Documents					
AA 6,255,192B1 07/03/01 Dornisch 438 430 09/09 BB 6,268,291B1 07/31/01 Andricacos et al. 438 694 12/03 CC 6,287,968B1 09/11/01 Yu et al. 438 675 01/04 DD 6,297,158B1 10/02/01 Liu et al. 438 687 05/31 EE 6,328,871B1 12/11/01 Ding et al. 205 183 08/16 FF 6,368,967B1 04/09/02 Besser 438 687 05/04 GG 6,376,370B1 04/23/02 Farrar 438 687 05/02 HH 6,391,777B1 05/21/02 Chen et al. 438 686 02/07 Foreign Patent or Published Foreign Patent Application Examiner No. No. Date Patent Office Class Class Yes N JJ KK LL MM NN							Sub-	Fi	ling	
BB 6,268,291B1 07/31/01 Andricacos et al. 438 694 12/03	Initial		Patent No.	Date	Patentee	Class	class	D	ate	
CC 6,287,968B1 09/11/01 Yu et al. 438 675 01/04 DD 6,297,158B1 10/02/01 Liu et al. 438 687 05/31 EE 6,328,871B1 12/11/01 Ding et al. 205 183 08/16 FF 6,368,967B1 04/09/02 Besser 438 687 05/04 GG 6,376,370B1 04/23/02 Farrar 438 678 01/18 HH 6,391,777B1 05/21/02 Chen et al. 438 687 05/02 V II 6,429,121B1 08/06/02 Hopper et al. 438 686 02/07 Foreign Patent or Published Foreign Patent Application Examiner Document Publication Country or Sub- Translat Initial No. No. Date Patent Office Class Ves N JJ KK	77/	AA	6,255,192B1	07/03/01	Dornisch	438	430	09	9/09/98	
DD 6,297,158B1 10/02/01 Liu et al. 438 687 05/31 EE 6,328,871B1 12/11/01 Ding et al. 205 183 08/16 FF 6,368,967B1 04/09/02 Besser 438 687 05/04 GG 6,376,370B1 04/23/02 Farrar 438 678 01/18 HH 6,391,777B1 05/21/02 Chen et al. 438 687 05/02 II 6,429,121B1 08/06/02 Hopper et al. 438 686 02/07 Foreign Patent or Published Foreign Patent Application Examiner No. No. Date Patent Office Class Translat Ves No. Ves No. Ves No. Ves No. JJ KK JJ JJ JJ JJ JJ		BB	6,268,291B1	07/31/01	Andricacos et al.	438	694	12	2/03/98	
EE 6,328,871B1 12/11/01 Ding et al. 205 183 08/16 FF 6,368,967B1 04/09/02 Besser 438 687 05/04 GG 6,376,370B1 04/23/02 Farrar 438 678 01/18 HH 6,391,777B1 05/21/02 Chen et al. 438 687 05/02 II 6,429,121B1 08/06/02 Hopper et al. 438 686 02/07 Foreign Patent or Published Foreign Patent Application Examiner Initial No. No. Date Patent Office Class Class Yes N JJ KK LL MM NN		CC	6,287,968B1	09/11/01	Yu et al.	438	675	01	/04/99	
FF 6,368,967B1 04/09/02 Besser 438 687 05/04 GG 6,376,370B1 04/23/02 Farrar 438 678 01/18 HH 6,391,777B1 05/21/02 Chen et al. 438 687 05/02 II 6,429,121B1 08/06/02 Hopper et al. 438 686 02/07 Foreign Patent or Published Foreign Patent Application Examiner Initial No. No. Date Patent Office Class Sub- Class Ves No. JJ KK		DD	6,297,158B1	10/02/01	Liu et al.	438	687	0.5	5/31/00	
GG 6,376,370B1 04/23/02 Farrar		EE	6,328,871B1	12/11/01	Ding et al.	205	183	08	3/16/99	
HH 6,391,777B1 05/21/02 Chen et al. 438 687 05/02 II 6,429,121B1 08/06/02 Hopper et al. 438 686 02/07		FF	6,368,967B1	04/09/02	Besser	438	687	05	5/04/00	
II 6,429,121B1 08/06/02 Hopper et al.		GG	6,376,370B1	04/23/02	Farrar	438	678	01	/18/00	
Foreign Patent or Published Foreign Patent Application Examiner Initial No. No. Date Patent Office Class class Yes N JJ KK LL MM NN NN Other Documents Examiner Initial No. Author, Title, Date, Place (e.g. Journal) of Publication		HH	6,391,777B1	05/21/02	Chen et al.	438	687	0.5	5/02/01	
Examiner Initial No. No. Date Patent Office Class class Yes No. JJ	V	II	6,429,121B1	08/06/02	Hopper et al.	438	686	02	2/07/01	
Examiner Initial No. No. Date Patent Office Class class Yes No. JJ										
Examiner Initial No. No. Date Patent Office Class Class Yes No. Date Patent Office Class Class Yes No. LL No. No. Date Patent Office Class Class Yes No. No. No. Date Patent Office Class Class Yes No.		F	oreign Patent	or Published	d Foreign Patent Ap	plicatio	n			
SKK LL LL MM NN Other Documents Examiner Initial No. Author, Title, Date, Place (e.g. Journal) of Publication OO	Examiner							Tran	slation	
KK LL MM NN Other Documents Examiner Initial No. Author, Title, Date, Place (e.g. Journal) of Publication OO	Initial	No.	No.	Date	Patent Office	Class	class	Yes	No	
Control of Publication Other Documents Examiner Initial No. Author, Title, Date, Place (e.g. Journal) of Publication OO		JJ			7					
Other Documents Examiner Initial No. Author, Title, Date, Place (e.g. Journal) of Publication OO		KK								
Other Documents Examiner Initial No. Author, Title, Date, Place (e.g. Journal) of Publication OO		LL			1/		Î			
Examiner Initial No. Author, Title, Date, Place (e.g. Journal) of Publication OO	MM			V						
Examiner Initial No. Author, Title, Date, Place (e.g. Journal) of Publication OO		NN		/	1					
Examiner Initial No. Author, Title, Date, Place (e.g. Journal) of Publication OO					· · · · · · · · · · · · · · · · · · ·		•			
Initial No. Author, Title, Date, Place (e.g. Journal) of Publication OO				Other D	ocuments					
00	Examiner									
00	Initial	No.	Author, Title,	Date, Place	(e.g. Journal) of Publ	ication				
PP /		00						····		
PP /				/						
, , , , , , , , , , , , , , , , , , ,		PP								

Date Considered
4/6/04 Examiner Date Considered 4/6/04

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

QQ

Examiner

Form 1440	(Modif	ind)		Attu Deekst No		A1:	4!	T
Form 1449 (Modified)			Atty Docket No.		Application No.:			
Information Disclosure			01-471/1D / LSI1P172D1 Filed Herewith					
Statement By Applicant			Applicant: 10 772 133 CATABAY et al.					
34	accinicini	Бу Аррисаі	IL	Filing Date		Group	,	
(Use S	everal S	heets if Neces	ssary)	Filing Date Herewith 2/3/04		Oroup Unassig	ned	
			U.S. Paten	t Documents				
Examiner						Sub-	F	iling
Initial	No.	Patent No.	Date	Patentee	Class	class		ate
7~1	AAA	6,440,849B1	08/27/02	Merchant et al.	438	658	1	0/18/99
	BBB	6,445,070B1	09/03/02	Wang et al.	257	751	0	1/29/01
	CCC	6,461,675B2	10/08/02	Paranjpe et al.	427	250	0	7/10/98
V	DDD	6,465,376B2	10/15/02	Uzoh et al.	438	927	0	8/18/99
	EEE				/			
	FFF				<i>Y</i>			
	GGG			/	1	1		
	ННН			/				•
	III			/			_	· · · · · · · · · · · · · · · · · · ·
	L		•					
	For	reign Patent	or Publishe	d Foreign Patent App	olication	1		
Examiner		Document	Publication	Country or		Sub-	Tran	slation
Initial	No.	No.	Date	Patent Office	Class	class	Yes	No
	JJJ			/				
	KKK							
	LLL							
	MMM	1						
	NNN							
			0.4 D		•		•	
Examiner	1	T	Otner I)	ocuments				
Initial	NIO	Author Tit	la Data Ala	as (s. s. Januard) af Dui	h1:4:	_		
Illitiai	No.		ie, Date,/Pia	ce (e.g. Journal) of Pu	dification	1		
	000							
	PPP							
	'''							
	QQQ		/					
	الممم	/						
Examiner			SWEN	Date Considered	4/6/0	16		
		1 · N/	xwien		71010	7		

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.